


<b>Search Notes</b>  	<b>Application/Control No.</b>  10651058	<b>Applicant(s)/Patent Under Reexamination</b>  SHIMADA ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	181,187,317	1/8/07	SCC
707	2,3,10	"	"
715	508,506	"	"
706	14,25,41	"	"
435	193,320.1,325,252.3	"	"
434	353,362,358,201	"	"
536	23.2	"	"
382	181	3/26/08	SCC
434	353,358	3/26/08	SCC
UP-DATE ABOVE SEARCH.		3/26/08	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/8/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY .	3/26/08	SCC
382/ 181, 187, 317. CCLS. US-PATENT ONLY , SEE TEXT SEARCH.	3/26/08	SCC
434/353, 358, 362, 201. CCLS. "	3/26/08	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	3/26/08	SCC
SEARCH IEEE OR INSPEC DATA BASE.	3/26/08	SCC
715/ 506, 508 , ABOLISH	3/26/08	SCC
UP-DATE THE ABOVE SEARCH.	3/26/08	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	181	3/26/08	SCC
434	353,358	3/26/08	SCC